Dirac charge dynamics in graphene by infrared spectroscopy

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A remarkable manifestation of the quantum character of electrons in matter is offered by graphene, a single atomic layer of graphite. Unlike conventional solids where electrons are described with the Schrödinger equation, electronic excitations in graphene are governed by the Dirac hamiltonian1. Some of the intriguing electronic properties of graphene, such as massless Dirac quasiparticles with linear energy-momentum dispersion, have been confirmed by recent observations²⁻⁵. Here, we report an infrared spectromicroscopy study of charge dynamics in graphene integrated in gated devices. Our measurements verify the expected characteristics of graphene and, owing to the previously unattainable accuracy of infrared experiments, also uncover significant departures of the quasiparticle dynamics from predictions made for Dirac fermions in idealized, freestanding graphene. Several observations reported here indicate the relevance of many-body interactions to the electromagnetic response of graphene.

We investigated the reflectance $R(\omega)$ and transmission $T(\omega)$ of graphene samples on a SiO₂/Si substrate (inset of Fig. 1a) as a function of gate voltage $V_{\rm g}$ at 45 K (see the Methods section). We start with data taken at the charge-neutrality point $V_{\rm CN}$: the gate voltage corresponding to the minimum d.c. conductivity and zero total charge density (inset of Fig. 1c). Figure 1a shows $R(\omega)$ of a graphene gated structure (graphene/SiO₂/Si) at $V_{\rm CN}=3$ V normalized by reflectance of the substrate $R_{\rm sub}(\omega)$. $R_{\rm sub}(\omega)$ is dominated by a minimum around 5,500 cm⁻¹ due to interference effects in SiO₂. A remarkable observation is that a monolayer of undoped graphene markedly modifies the interference minimum of the substrate leading to a suppression of $R_{\rm sub}(\omega)$ by as much as 15%. This observation is significant because it enables us to evaluate the conductivity of graphene near the interference structure, as will be discussed below.

Both reflectance and transmission spectra of graphene structures can be modified by a gate voltage. Figure 1b,c shows these modifications at various gate voltages normalized by data at $V_{\rm CN}$: $R(V)/R(V_{\rm CN})$ and $T(V)/T(V_{\rm CN})$, where $V=V_{\rm g}-V_{\rm CN}$. These data correspond to the Fermi energy $E_{\rm F}$ on the electron side and similar behaviour was observed with $E_{\rm F}$ on the hole side (not shown). At low voltages (<17 V), we found a dip in $R(V)/R(V_{\rm CN})$

spectra. With increasing bias, this feature evolves into a peak—dip structure and systematically shifts to higher frequency. The $T(V)/T(V_{\rm CN})$ spectra reveal a peak at all voltages, which systematically hardens with increasing bias. A voltage-induced increase in transmission $(T(V)/T(V_{\rm CN})>1)$ signals a decrease of the absorption with bias. Most interestingly, we observed that the frequencies of the main features in $R(V)/R(V_{\rm CN})$ and $T(V)/T(V_{\rm CN})$ all evolve approximately as \sqrt{V} .

To explore the quasiparticle dynamics under applied voltages, it is imperative to first discuss the two-dimensional (2D) optical conductivity of charge-neutral graphene, $\sigma_1(\omega, V_{CN}) + i\sigma_2(\omega, V_{CN})$, extracted from a multilayer analysis of the devices (see the Methods section). Theoretical analysis⁶⁻⁸ predicts a constant 'universal' 2D conductivity $\sigma_1(\omega, V_{\rm CN}) = \pi e^2/2h$ for ideal undoped graphene. Our $R(\omega)/R_{\text{sub}}(\omega)$ data are consistent with this prediction. Figure 1a shows a comparison between the experimental $R(\omega)/R_{\text{sub}}(\omega)$ spectrum and model spectra generated assuming constant $\sigma_1(\omega, V_{\rm CN})$ values. The constant universal conductivity offers a good agreement (within ±15%) with the experimental spectra in the range 4,000-6,500 cm⁻¹. Outside this spectral region, our infrared measurements do not allow us to unambiguously determine the absolute value of $\sigma_1(\omega, V_{CN})$; therefore, the uncertainty of $\sigma_1(\omega, V_{CN})$ increases as shown by the shaded region weighted around the $\pi e^2/2h$ value in Fig. 2a. However, recent infrared studies of graphene revealed a constant conductivity $\sigma_1(\omega, V_{\rm CN}) = \pi e^2/2h$ between 2,400 and 24,000 cm⁻¹ (ref. 9 and Mak, K.F. & Heinz, T. 2008 APS March Meeting, Abstract: L29.00006, unpublished). The universal conductivity is only weakly modified in bulk highly ordered pyrolytic graphite¹⁰ and extends down to 800 cm⁻¹. Thus, in the following discussion, we will assume $\sigma_1(\omega, V_{\rm CN}) = \pi e^2/2h$ throughout the entire range of our data.

Electrostatic doping of graphene introduces two fundamental changes in the optical conductivity $\sigma_1(\omega,V)+i\sigma_2(\omega,V)$: a strong Drude component formed in the far-infrared with $\sigma_1(\omega\to 0)=4$ –100 $\pi e^2/2h$ accompanied by a shift in the onset of interband transitions at $2E_{\rm F}$, as schematically shown in the inset of Fig. 2b. To investigate these effects, we obtained

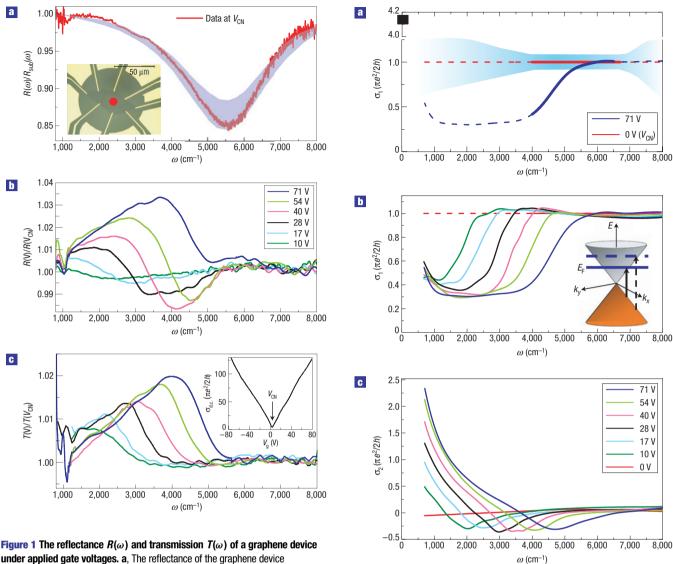


Figure 1 The reflectance $R(\omega)$ and transmission $T(\omega)$ of a graphene device under applied gate voltages. a, The reflectance of the graphene device (graphene/SiO₂/Si) $R(\omega)$ normalized by that of the SiO₂/Si substrate $R_{\text{sub}}(\omega)$ at the charge-neutrality voltage V_{CN} . A set of $R(\omega)/R_{\text{sub}}(\omega)$ spectra generated from the multilayer model using a constant $\sigma_1(\omega, V_{\text{CN}})$ in the range of $(1\pm 0.15)\pi e^2/2h$ are shown as the shaded area. The upper and lower boundary of the shaded area are defined by $\sigma_1(\omega, V_{\text{CN}})$ with values of $0.85^*\pi e^2/2h$ and $1.15^*\pi e^2/2h$, respectively. Inset: A photograph of a graphene device together with a schematic diagram of the focused synchrotron beam (red dot). \mathbf{b} , \mathbf{c} , $R(V)/R(V_{\text{CN}})$ (\mathbf{b}) and $T(V)/T(V_{\text{CN}})$ (\mathbf{c}) spectra of the graphene device at several voltages corresponding to E_{F} on the electron side, where $V = V_{\text{Q}} - V_{\text{CN}}$. The inset of \mathbf{c} shows the smoothed d.c. conductivity data of the sample as a function of gate voltage V_{Q} .

 $\sigma_1(\omega,V)+i\sigma_2(\omega,V)$ (Fig. 2b,c) from voltage-dependent reflectance and transmission spectra (see the Methods section). The key features in the conductivity spectra are independent of uncertainties in $\sigma_1(\omega,V_{\rm CN})$ discussed above. Regardless of the choice of $\sigma_1(\omega,V_{\rm CN})$, under applied biases, we observe a suppression of the conductivity compared with $\sigma_1(\omega,V_{\rm CN})$ and a well-defined threshold structure above which the conductivity recovers the universal value $\pi e^2/2h$. The energy of the threshold structure systematically increases with voltage, a natural expectation for a transition occurring at $2E_{\rm F}$. With a scattering rate $1/\tau=30\,{\rm cm}^{-1}$ at 71 V independently obtained from transport data, the Drude mode is narrow and confined

Figure 2 The optical conductivity of graphene at different voltages. a, The real part of the 2D optical conductivity $\sigma_1(\omega)$ at V_{CN} and 71 V. The solid red line shows the region where our data support the universal result. The uncertainty of $\sigma_1(\omega, V_{\text{CN}})$ is shown by the shaded area with the theoretical $\sigma_1(\omega) = \pi e^2/2h$ plotted as the red dashed line. The blue dashed line is $\sigma_1(\omega)$ at 71 V evaluated for the theoretical spectra: $\sigma_1(\omega, V_{\text{CN}}) = \pi e^2/2h$ (red dashed line). The key spectral features of $\sigma_1(\omega, V)$ are independent of uncertainties in $\sigma_1(\omega, V_{\text{CN}})$ indicated by the shaded area, as discussed in the text. Black square on the left axis: d.c. conductivity at V_{CN} . b,c, $\sigma_1(\omega)$ (b) and $\sigma_2(\omega)$ (c) of graphene at several voltages with respect to V_{CN} corresponding to E_{F} on the electron side based on $\sigma_1(\omega, V_{\text{CN}}) = \pi e^2/2h$. The absolute values of the $\sigma_2(\omega)$ spectra in c have uncertainties due to the uncertainties of $\sigma_1(\omega, V_{\text{CN}})$ as discussed in the text. The inset of b shows the band structure of graphene near the Dirac point and the interband transition at $2E_{\text{F}}$.

below the low- ω cutoff of our measurements. We stress that the two voltage-induced transformations of the conductivity, the intraband mode and the onset of interband absorption at $2E_{\rm F}$, are interdependent as suggested by our data. Indeed, assuming the intraband component can be described with a simple Drude formula $\sigma_1(\omega) = \sigma_{\rm d.c.}/(1+\omega^2\tau^2)$ using $\sigma_{\rm d.c.}$ and $1/\tau$ obtained from transport measurements, we find that the spectral weight

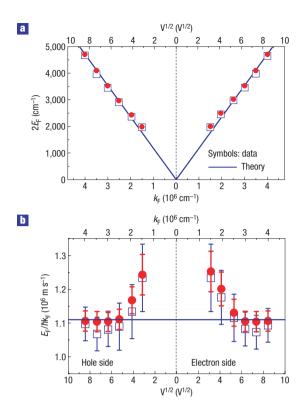


Figure 3 The Fermi energy $E_{\rm F}$ and the ratio of $E_{\rm F}$ to the Fermi wave vector $E_{\rm F}/\hbar k_{\rm F}$. The magnitude of $E_{\rm F}/\hbar k_{\rm F}$ is closely related to the Fermi velocity $v_{\rm F}$ as discussed in the text . **a**, The magnitude of $2E_{\rm F}$ plotted as a function of $V^{1/2}$ and $k_{\rm F}$ for the electron and hole sides with respect to the charge-neutrality voltage. Red solid symbols: $2E_{\rm F}$ extracted from the minimum in the $\sigma_2(\omega,V)$ spectra. Blue open symbols: $2E_{\rm F}$ extracted from the centre of the $2E_{\rm F}$ threshold in $\sigma_1(\omega,V)$. The uncertainties of the $2E_{\rm F}$ values discussed in the Methods section do not exceed the size of the symbols. Solid lines are theoretical $2E_{\rm F}$ values using $v_{\rm F}=1.11\times 10^6~{\rm m\, S^{-1}}$. **b**, Symbols: $E_{\rm F}/\hbar k_{\rm F}$ as a function of $V^{1/2}$ and $k_{\rm F}$. The blue line corresponds to a $v_{\rm F}$ value of $1.11\times 10^6~{\rm m\, S^{-1}}$. The error bars reflect uncertainties in the determination of the Fermi energy $2E_{\rm F}$ from the conductivity data $\delta(E_{\rm F})$ discussed in the Methods section and are calculated as $\delta(E_{\rm F})/\hbar k_{\rm F})=\delta(E_{\rm F})/(\hbar\sqrt{\pi\,C_{\rm G}\,V/e})$.

removed from $\omega < 2E_{\rm F}$ is recovered under the Drude structure, such that the total oscillator strength given by $\int_0^{\Omega_{\rm c}} \sigma_1(\omega) \, {\rm d}\omega$ is conserved at any bias with a cutoff frequency $\Omega_{\rm c} = 8,000 \, {\rm cm}^{-1}$.

Next, we extracted Fermi energy values from the $2E_{\rm F}$ threshold using two different methods (see the Methods section). We found that the $2E_{\rm F}$ values (Fig. 3a) are symmetric for biases delivering either holes or electrons to graphene. Moreover, $2E_{\rm F}$ increases with voltage approximately as \sqrt{V} (deviations from the square-root law at small biases will be discussed below). Note that $E_{\rm F}$ of Dirac fermions scales with the 2D carrier density N as $E_{\rm F} = \hbar \nu_{\rm F} \sqrt{\pi N}$ (refs 2,3), where $\nu_{\rm F}$ is the Fermi velocity. In our devices, $N = C_{\rm g} V/e$, where $C_{\rm g} = 115\,{\rm aF\,\mu m^{-2}}$ is the gate capacitance per unit area. Therefore, the observed \sqrt{V} dependence of $2E_{\rm F}$ substantiates that graphene samples integrated in gated devices are governed by Dirac quasiparticles.

Interestingly, the $2E_{\rm F}$ threshold in $\sigma_1(\omega,V)$ shows a width of about 1,400 cm⁻¹ that is independent of gate voltage and therefore of carrier density N, irrespective of a sevenfold enhancement of N between 10 and 71 V. This effect is much stronger than the theoretical estimate for thermal smearing of the $2E_{\rm F}$ feature at 45 K

(refs 7,8), which is about $500\,\mathrm{cm^{-1}}$. A recent theoretical study¹¹ showed that disorder effects and electron–phonon coupling are needed to account for the width of the $2E_{\mathrm{F}}$ threshold in our data. Apart from that, a spatial variation of local E_{F} values observed in graphene on $\mathrm{SiO_2/Si}$ substrates (ref. 12 and Brar, V. *et al.*, 2008 APS March Meeting, Abstract: U29.00003, unpublished) will inevitably lead to a broadening of the absorption onset at $2E_{\mathrm{F}}$ in $\sigma_1(\omega)$, because infrared measurements register the absorption averaged over a large area (a few micrometres in our experiments). The origin of the inhomogeneity of E_{F} in graphene is still an open question¹², which needs to be explored using spatially resolved probes such as near-field infrared conductivity studies capable of probing the response of a material with nanometre resolution over a large area¹³.

Our study has uncovered several new properties of graphene that are beyond the ideal Dirac fermion picture¹⁴. First, our study revealed unexpected features of $\sigma_1(\omega, V)$ below $2E_F$. The band structure of ideal graphene implies that the interband transition at $2E_F$ is the lowest electronic excitation in the system apart from the Drude response at $\omega = 0$. Therefore, we anticipate finding $\sigma_1(\omega, V) \approx 0$ up to the $2E_F$ threshold, provided the Drude scattering rate is much smaller than $2E_F$. This latter condition is fulfilled for all data in Fig. 2, and yet we registered significant conductivity below $2E_{\rm F}$ (see the Supplementary Information). This result has not been anticipated by theories developed for Dirac fermions⁶⁻⁸. Both extrinsic and intrinsic effects may give rise to the residual conductivity in Fig. 2. Among the former, charged impurities and unitary scatterers (edge defects, cracks, vacancies and so on) were shown to induce considerable residual conductivity below $2E_{\rm F}$ (ref. 11). However, the theoretical residual absorption in ref. 11 is systematically suppressed with voltage, whereas this suppression was not observed in our data. In addition, the magnitude of the theoretical residual absorption is smaller compared with experimental values in Fig. 2. Therefore, it is likely that other mechanisms are also responsible for the residual conductivity in our data. One intriguing interpretation of the residual conductivity is in terms of many-body interactions, which are known to produce a strong frequency-dependent quasiparticle scattering rate $1/\tau(\omega)$. It is predicted theoretically that $1/\tau(\omega)$ in graphene increases with frequency owing to electron-electron^{15,16} and electron-phonon interactions¹⁷. The energy-dependent scattering rate initiates a marked enhancement of the conductivity compared with the lorentzian form prescribed by the Drude model. Such an enhancement in mid-infrared frequencies has been observed in many systems 18-20.

A closer inspection of the voltage dependence of the $2E_F$ feature uncovers marked departures from the behaviour anticipated within a single particle picture of graphene. To highlight these deviations, we plot $2E_F$ as a function of the Fermi wave vector k_F based on $k_{\rm F} = \sqrt{\pi N} = \sqrt{\pi C_{\rm g} V/e}$, as shown in Fig. 3a. The $E_{\rm F}(k_{\rm F})$ plot has a clear physical meaning: it is a direct representation of the band dispersion. We then examine the ratio $E_{\rm F}/\hbar k_{\rm F}$, which is directly related to the Fermi velocity $v_{\rm F}$. The $E_{\rm F}/\hbar k_{\rm F}$ plot as a function of $V^{1/2}$ and $k_{\rm F}$ in Fig. 3b reveals a departure from linear dispersion with a single value of $E_{\rm F}/\hbar k_{\rm F}$ expected within a single particle picture. Moreover, $E_{\rm F}/\hbar k_{\rm F}$ increases systematically with decreasing $k_{\rm F}$ values compared with that at high $k_{\rm F}$ values. The observed systematic enhancement of $E_{\rm F}/\hbar k_{\rm F}$ at low $k_{\rm F}$ is indicative of manybody interactions^{14,21,22}. Signatures of band renormalization were also observed in a previous magneto-optical study of graphene⁴. Importantly, even the smallest $E_{\rm F}/\hbar k_{\rm F}$ values in Fig. 3b are higher than that of the bulk graphite²³ ($\sim 0.9 \times 10^6 \,\mathrm{m\,S^{-1}}$), which also supports the hypothesis of $E_{\rm F}/\hbar k_{\rm F}$ renormalization in graphene. Complementary information on the $E_{\rm F}/\hbar k_{\rm F}$ renormalization in graphene can be obtained from photoemission, which is another

potent probe of many-body effects in solids. Currently available photoemission data were all collected for epitaxial graphene grown on SiC (refs 24,25). This complicates a direct comparison with infrared results for exfoliated samples on SiO₂/Si substrates reported here. We conclude by noting that the strong deviations of the experimental electromagnetic response from a simple single particle picture of graphene reported in our study challenge current theoretical conceptions of fundamental properties of this interesting form of carbon and also have implications for its potential applications in opto-electronics.

Note added in proof. After the submission of our paper, we became aware of another work on gate tunable infrared properties of graphene²⁶.

METHODS

SAMPLE FABRICATION AND INFRARED MEASUREMENTS

In the graphene devices studied here, monolayer graphene mechanically cleaved from Kish graphite was deposited onto an infrared transparent $SiO_2(300 \text{ nm})/Si$ substrate^{2,3}, which also serves as the gate electrode. Then, standard fabrication procedures were used to define multiple Cr/Au (3/35 nm) contacts to the sample. The devices studied here exhibit mobility as high as 8,700 cm² V⁻¹ s⁻¹ measured at carrier densities of \sim 2 × 10^{12} cm². The characteristic half-integer quantum Hall effect is observed in these samples^{2,3}, confirming the single layer nature of our specimen. Infrared experiments were carried out using an infrared microscope operating with a synchrotron source at the Advanced Light Source in the frequency range of 700–8,000 cm². The synchrotron beam is focused in a diffraction-limited spot, which is smaller than the sample. We measured the reflectance $R(\omega)$ and transmission $T(\omega)$ of the graphene devices as a function of gate voltage V_o with simultaneous monitoring of the d.c. resistivity.

TEMPERATURE OF THE GRAPHENE SAMPLE

Data reported here were obtained in a micro-cryostat with the sample mounted on a coldfinger in vacuum. The temperature of our graphene sample is warmer than that of the coldfinger, owing to thermal radiation from room-temperature KBr optical windows and electrical isolation of the devices from the coldfinger that compromises thermal contact. A sensor mounted in the immediate proximity to the Si substrate of the devices read $T=45\,\mathrm{K}$ at the lowest temperatures attainable at the coldfinger. Because both the temperature sensor and the device are in a nearly identical environment, we assumed this reading to be accurate for graphene as well.

EXTRACTING THE OPTICAL CONSTANTS OF GRAPHENE

The graphene device contains four layers: (1) graphene with 2D optical conductivity $\sigma(\omega) = \sigma_1(\omega) + i\sigma_2(\omega)$, (2) SiO₂ gate insulator, (3) Si accumulation layer that forms at the interface of SiO₂/Si under the applied bias and (4) Si substrate. Properties of layers 2 and 4 are independent of the gate voltage, whereas layers 1 and 3 are systematically modified by $V_{\rm g}$. In our analysis of these multilayer structures, we followed the protocol detailed in ref. 27. Specifically, we carried out reflection, transmission and ellipsometric measurements on the Si substrates and SiO2/Si wafers used in our devices and thus obtained the optical constants of layers 2 and 4. We then investigated infrared properties of test devices Ti/SiO2/Si as a function of gate voltage and thus extracted the optical constants of the Si accumulation layer in wafers used for graphene devices. We find that the response of the Si accumulation layer is confined to far-infrared frequencies²⁸ and gives negligible contribution to mid-infrared data in Fig. 1. Finally, we used a multi-oscillator fitting procedure²⁷ to account for the contribution of $\sigma(\omega)$ of graphene to the reflectance and transmission spectra shown in Fig. 1 using standard methods for multilayered structures.

EXTRACTING FERMI ENERGY $E_{\rm F}$ FROM CONDUCTIVITY SPECTRA

Because of the broadening of the $2E_F$ threshold in $\sigma_1(\omega, V)$, the E_F values can be determined most accurately from the imaginary part of the optical

conductivity spectra $\sigma_2(\omega,V)$ shown in Fig. 2c. Indeed, these spectra reveal a sharp minimum at $\omega=2E_{\rm F}$ in agreement with a previous theoretical prediction²⁹. The minimum in the $\sigma_2(\omega,V)$ spectrum is found from the frequency where the derivative of $\sigma_2(\omega,V)$ with respect to frequency is zero. The uncertainties of $2E_{\rm F}$ obtained from this method are related to the accuracy in defining the minimum in the $\sigma_2(\omega,V)$ spectrum. Alternatively, $2E_{\rm F}$ values can be extracted from the centre frequency of the $2E_{\rm F}$ threshold in $\sigma_1(\omega,V)$. The second method has larger uncertainties, as shown in Fig. 3, due to the ambiguity of defining the centre of the $2E_{\rm F}$ threshold in $\sigma_1(\omega,V)$.

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